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Table of Contents

Welcome from the General and Program Chairs	xiii
ITC Technical Paper Evaluation and Selection Process	xiv

Session 1A

A Fast and Low Cost Embedded Test Solution for CMOS Image Sensors	1
<i>Julia Lefevre (STMicroelectronics, France), Philippe Debaud (STMicroelectronics, France), Patrick Girard (LIRMM, University of Montpellier/CNRS, France), and Arnaud Virazel (LIRMM, University of Montpellier/CNRS, France)</i>	
ACE-Pro: Reduction of Functional Errors with ACE Propagation Graph	10
<i>Dun-An Yang (National Tsing Hua University, Taiwan), Yu-Teng Chang (National Tsing Hua University, Taiwan), Ting-Shou Hsu (National Tsing Hua University, Taiwan), Jing-Jia Liou (National Tsing Hua University, Taiwan), and Harry H. Chen (MediaTek Inc., Computing and AI Technology Group, Taiwan)</i>	
Testability-Enhancing Resynthesis of Reconfigurable Scan Networks	20
<i>Natalia Lylyna (University of Stuttgart, Germany), Chih-Hao Wang (University of Stuttgart, Germany), and Hans-Joachim Wunderlich (University of Stuttgart, Germany)</i>	

Session 1B

Adaptive NN-Based Root Cause Analysis in Volume Diagnosis for Yield Improvement	30
<i>Xin Huang (Huawei Technology Co. Ltd.), Min Qin (Huawei Technology Co. Ltd.), Ruosheng Xu (Huawei Technology Co. Ltd.), Cheng Chen (Huawei Technology Co. Ltd.), Shangling Jui (Huawei Technology Co. Ltd.), Zhihao Ding (Huawei Technology Co. Ltd.), Pengyun Li (Huawei Technology Co. Ltd.), and Yu Huang (Huawei Technology Co. Ltd.)</i>	
Machine Learning for Circuit Aging Estimation under Workload Dependency	37
<i>Florian Klemme (University of Stuttgart, Germany) and Hussam Amrouch (University of Stuttgart, Germany)</i>	

Minimum Operating Voltage Prediction in Production Test Using Accumulative Learning	47
<i>Yen-Ting Kuo (National Taiwan University, Taiwan), Wei-Chen Lin (National Taiwan University, Taiwan), Chun Chen (National Taiwan University, Taiwan), Chao-Ho Hsieh (National Taiwan University, Taiwan), James Chien-Mo Li (National Taiwan University, Taiwan), Eric Jia-Wei Fang (MediaTek Inc., Taiwan), and Sung S.-Y. Hsueh (MediaTek Inc., Taiwan)</i>	

Session 1D

Smart Sampling for Efficient System Level Test: A Robust Machine Learning Approach	53
<i>Chenwei Liu (Huawei Technologies) and Jie Ou (Huawei Technologies)</i>	
The Security Enhancement Techniques of the Double-Layer PUF against the ANN-Based Modeling Attack	63
<i>Yongliang Chen (Peking University Shenzhen Graduate School, China & Peng Cheng Lab, China), Xiaole Cui (Peking University Shenzhen Graduate School, China), Wenqiang Ye (Peking University Shenzhen Graduate School, China), and Xiaoxin Cui (Peking University, China)</i>	

Session 2A

Efficient Fault-Criticality Analysis for AI Accelerators Using a Neural Twin	73
<i>Arjun Chaudhuri (Duke University, USA), Ching-Yuan Chen (Duke University, USA), Jonti Talukdar (Duke University, USA), Siddarth Madala (Duke University, USA), Abhishek Dubey (National Cancer Institute, USA), and Krishnendu Chakrabarty (Duke University, USA)</i>	
On-Line Functional Testing of Memristor-Mapped Deep Neural Networks Using Backdoored Checksums	83
<i>Ching-Yuan Chen (Duke University, USA) and Krishnendu Chakrabarty (Duke University, USA)</i>	
Efficient Functional In-Field Self-Test for Deep Learning Accelerators	93
<i>Yi He (University of Chicago, USA), Takumi Uezono (Hitachi Ltd., Japan), and Yanjing Li (University of Chicago, USA)</i>	

Session 2B

Wafer-Level Variation Modeling for Multi-Site RF IC Testing via Hierarchical Gaussian Process	103
<i>Michihiro Shintani (Nara Institute of Science and Technology, Japan), Riaz-Ul-Haque Mian (Nara Institute of Science and Technology, Japan), Michiko Inoue (Nara Institute of Science and Technology, Japan), Tomoki Nakamura (Sony Semiconductor Manufacturing Corp., Japan), Masuo Kajiyama (Sony Semiconductor Manufacturing Corp., Japan), and Makoto Eiki (Sony Semiconductor Manufacturing Corp., Japan)</i>	

Semi-Supervised Wafer Map Pattern Recognition Using Domain-Specific Data Augmentation and Contrastive Learning	113
<i>Hanbin Hu (University of California - Santa Barbara, USA), Chen He (NXP Semiconductors, USA), and Peng Li (University of California - Santa Barbara, USA)</i>	
Brain-Inspired Computing for Wafer Map Defect Pattern Classification	123
<i>Paul R. Genssler (University of Stuttgart, Germany) and Hussam Amrouch (University of Stuttgart, Germany)</i>	

Session 2D

Study on High-Accuracy and Low-Cost Recycled FPGA Detection	133
<i>Faisal Ahmed (Nara Institute of Science and Technology, Japan), Michihiro Shintani (Nara Institute of Science and Technology, Japan), and Michiko Inoue (Nara Institute of Science and Technology, Japan)</i>	
Testing STT-MRAM: Manufacturing Defects, Fault Models, and Test Solutions	143
<i>Lizhou Wu (TUDelft, The Netherlands), Siddharth Rao (IMEC, Belgium), Mottaqiallah Taouil (TUDelft, The Netherlands & CognitiveIC, The Netherlands), Erik Jan Marinissen (IMEC, Belgium), Gouri Sankar Kar (IMEC, Belgium), and Said Hamdioui (TUDelft, The Netherlands & CognitiveIC, The Netherlands)</i>	
Adaptive Methods for Machine Learning-Based Testing of Integrated Circuits and Boards	153
<i>Mengyun Liu (Duke University, USA) and Krishnendu Chakrabarty (Duke University, USA)</i>	

Session 3A

Impeccable Circuits III	163
<i>Shahram Rasoolzadeh (Radboud University, The Netherlands), Aein Rezaei Shahmirzadi (Ruhr University Bochum, Germany), and Amir Moradi (Ruhr University Bochum, Germany)</i>	
A BIST-Based Dynamic Obfuscation Scheme for Resilience against Removal and Oracle-Guided Attacks	170
<i>Jonti Talukdar (Duke University, USA), Siyuan Chen (Carnegie Mellon University, USA), Amitabh Das (AMD, USA), Sohrab Aftabjehani (Intel Corp., USA), Peilin Song (IBM T.J. Watson Research Center, USA), and Krishnendu Chakrabarty (Duke University, USA)</i>	
LL-ATPG: Logic-Locking Aware Test Using Valet Keys in an Untrusted Environment	180
<i>M Sazadur Rahman (University of Florida, USA), Henian Li (University of Florida, USA), Rui Guo (University of Florida, USA), Fahim Rahman (University of Florida, USA), Farimah Farahmandi (University of Florida, USA), and Mark Tehranipoor (University of Florida, USA)</i>	

Session 3B

- MINIature Interactive Offset Networks (MINIONS) for Wafer Map Classification 190
*Yueling (Jenny) Zeng (University of California - Santa Barbara, USA),
Li-C. Wang (University of California - Santa Barbara, USA), and
Chuanhe (Jay) Shan (University of California - Santa Barbara, USA)*
- Triplet Convolutional Networks for Classifying Mixed-Type WBM Patterns with Noisy Labels ... 200
*Chenwei Liu (Huawei Technologies, China) and Qiaoyue Tang (Huawei
Technologies, China)*
- Semi-Supervised Framework for Wafer Defect Pattern Recognition with Enhanced Labeling ... 208
*Leon Li-Yang Chen (NXP Semiconductors Taiwan Ltd., Taiwan), Katherine
Shu-Min Li (National Sun Yat-Sen University, Taiwan), Xu-Hao Jiang
(National Sun Yat-Sen University, Taiwan), Syng-Jyan Wang (National
Chung Hsing University, Taiwan), Andrew Yi-Ann Huang (NXP
Semiconductors Taiwan Ltd., Taiwan), Jwu E Chen (National Central
University, Taiwan), Hsing-Chung Liang (Chung Yuan Christian
University, Taiwan), and Chun-Lung Hsu (Industrial Technology Research
Institute, Taiwan)*

Session 4A

- Characterizing Corruptibility of Logic Locks Using ATPG 213
*Danielle Duvalsaint (Carnegie Mellon University, USA) and R. D.
(Shawn) Blanton (Carnegie Mellon University, USA)*
- SymbA: Symbolic Execution at C-Level for Hardware Trojan Activation 223
*Arash Vafaei (University of Florida, USA), Nick Hooten (Dynetics),
Mark Tehranipoor (University of Florida, USA), and Farimah Farahmandi
(University of Florida, USA)*

Session 4B

- Open-Short Normalization Method for a Quick Defect Identification in Branched Traces with
High-Resolution Time-Domain Reflectometry 233
*Yang Shang (Advantest (Singapore) Pte. Ltd., Singapore), Makoto
Shinohara (Advantest Corp., Japan), Eiji Kato (Advantest Corp.,
Japan), Masaichi Hashimoto (Advantest Corp., Japan), and Joanna Kiljan
(Qualcomm Technologies, Inc., USA)*
- Relevant Signals and Devices for Failure Analysis of Analog and Mixed-Signal Circuits 243
*Tommaso Melis (University of Grenoble Alpes, CNRS, France), Emmanuel
Simeu (University of Grenoble Alpes, CNRS, France), Luc Saury
(STMicroelectronics, France), and Etienne Auvray (Fastnet
Technologies, France)*
- Improving Volume Diagnosis and Debug with Test Failure Clustering and Reorganization 251
*Mu-Ting Wu (National Taiwan University, Taiwan), Cheng-Sian Kuo
(National Taiwan University, Taiwan), James Chien-Mo Li (National
Taiwan University, Taiwan), Chris Nigh (Qualcomm Technologies, Inc.,
USA), and Gaurav Bhargava (Qualcomm Technologies, Inc., USA)*

Session 4C

On Reduction of Deterministic Test Pattern Sets	260
<i>Stephan Eggersglüß (Siemens Digital Industries Software, USA), Sylwester Milewski (Poznań University of Technology, Poland), Janusz Rajski (Siemens Digital Industries Software, USA), and Jerzy Tyszer (Poznan University of Technology, Poland)</i>	
Analyzing and Mitigating Sensing Failures in Spintronic-Based Computing in Memory	268
<i>Mahta Mayahinia (Karlsruhe Institute of Technology, Germany), Christopher Münch (Karlsruhe Institute of Technology, Germany), and Mehdi B. Tahoori (Karlsruhe Institute of Technology, Germany)</i>	
Multi-Transition Fault Model (MTFM) ATPG Patterns towards Achieving 0 DPPB on Automotive Designs	278
<i>Jorge Corso (NXP Semiconductors, USA), Saidapet Ramesh (NXP Semiconductors, USA), Kumar Abishek (NXP Semiconductors, USA), Ley Teng Tan (NXP Semiconductors, Malaysia), and Chik Hooi Liew (NXP Semiconductors, Malaysia)</i>	

Session 5A

Revisit to Accurate ADC Testing with Incoherent Sampling Using Proper Sinusoidal Signal and Sampling Frequencies	284
<i>Keno Sato (ROHM Semiconductor, Japan), Takashi Ishida (ROHM Semiconductor, Japan), Toshiyuki Okamoto (ROHM Semiconductor, Japan), Tamotsu Ichikawa (ROHM Semiconductor, Japan), Jianglin Wei (Gunma University, Japan), Takayuki Nakatani (Gunma University, Japan), Yujie Zhao (Gunma University, Japan), Shogo Katayama (Gunma University, Japan), Shuhei Yamamoto (Gunma University, Japan), Anna Kuwana (Gunma University, Japan), Kazumi Hatayama (Gunma University, Japan), and Haruo Kobayashi (Gunma University, Japan)</i>	
Adaptive High Voltage Stress Methodology to Enable Automotive Quality on FinFET Technologies	289
<i>Stephen Traynor (NXP Semiconductor, USA), Chen He (NXP Semiconductor, USA), Yy Yu (NXP Semiconductor, USA), and Ken Klein (NXP Semiconductor, USA)</i>	
3.5 Gsps MIPI C-PHY Receiver Circuit for Automatic Test Equipment	294
<i>Seongkwan Lee (Samsung Electronics, South Korea), Minho Kang (Samsung Electronics, South Korea), Cheolmin Park (Samsung Electronics, South Korea), HyungSun Ryu (Samsung Electronics, South Korea), Jaemoo Choi (Samsung Electronics, South Korea), and Byunghyun Yim (Samsung Electronics, South Korea)</i>	
A Scalable Design Flow for Performance Monitors Using Functional Path Ring Oscillators	299
<i>Tobias Kilian (Infineon Technologies AG, Germany & Technical University of Munich, Germany), Heiko Ahrens (Infineon Technologies AG, Germany), Daniel Tille (Infineon Technologies AG, Germany), Martin Huch (Infineon Technologies AG, Germany), and Ulf Schlichtmann (Technical University of Munich, Germany)</i>	

Session 5B

Systematic Hardware Error Identification and Calibration for Massive Multisite Testing	304
<i>Praise O. Farayola (Iowa State University, USA), Isaac Bruce (Iowa State University, USA), Shravan K. Chaganti (Texas Instruments Inc., USA), Abdullah O. Obaidi (Texas Instruments Inc., USA), Abalhassan Sheikh (Texas Instruments Inc., USA), Srivaths Ravi (Texas Instruments Inc., USA), and Degang Chen (Iowa State University, USA)</i>	
WGrid: Wafermap Grid Pattern Recognition with Machine Learning Techniques	309
<i>Peter Yi-Yu Liao (NXP Semiconductors Taiwan Ltd., Taiwan), Katherine Shu-Min Li (National Sun Yat-Sen University, Taiwan), Leon Li-Yang Chen (NXP Semiconductors Taiwan Ltd., Taiwan), Sying-Jyan Wang (National Chung Hsing University, Taiwan), Andrew Yi-Ann Huang (NXP Semiconductors Taiwan Ltd., Taiwan), Ken Chau-Cheung Cheng (NXP Semiconductors Taiwan Ltd., Taiwan), Nova Cheng-Yen Tsai (NXP Semiconductors Taiwan Ltd., Taiwan), and Leon Chou (NXP Semiconductors Taiwan Ltd., Taiwan)</i>	
AAA: Automated On-ATE AI Debug of Scan Chain Failures	314
<i>Chris Nigh (Carnegie Mellon University, USA & Qualcomm Technologies, USA), Gaurav Bhargava (Qualcomm Technologies, USA), and R.D. Blanton (Carnegie Mellon University, USA)</i>	
Low Power Shift and Capture through ATPG-Configured Embedded Enable Capture Bits	319
<i>Yi Sun (Southern Methodist University, USA), Hui Jiang (Southern Methodist University, USA), Lakshmi Ramakrishnan (Southern Methodist University, USA), Jennifer Dworak (Southern Methodist University, USA), Kundan Nepal (University of St. Thomas, USA), Theodore Manikas (Southern Methodist University, USA), and R. Iris Bahar (Brown University, USA)</i>	

Session 5C

Testability-Aware Low Power Controller Design with Evolutionary Learning	324
<i>Min Li (The Chinese University of Hong Kong, Hong Kong), Zhengyuan Shi (The Chinese University of Hong Kong, Hong Kong), Zezhong Wang (Huawei Technologies Co., Ltd., China), Weiwei Zhang (Huawei Technologies Co., Ltd., China), Yu Huang (Huawei Technologies Co., Ltd., China), and Qiang Xu (The Chinese University of Hong Kong, Hong Kong)</i>	
An Automated Formal-Based Approach for Reducing Undetected Faults in ISO 26262 Hardware Compliant Designs	329
<i>Felipe Augusto da Silva (Cadence Design Systems, Germany & Delft University of Technology, The Netherlands), Ahmet Cagri Bagbaba (Cadence Design Systems, Germany), Said Hamdioui (Delft University of Technology, The Netherlands), and Christian Sauer (Cadence Design Systems, Germany)</i>	
Is Your Secure Test Infrastructure Secure Enough? Attacks Based on Delay Test Patterns Using Transient Behavior Analysis	334
<i>Sergej Meschkov (Karlsruhe Institute of Technology (KIT), Germany), Dennis R.E. Gnad (Karlsruhe Institute of Technology (KIT), Germany), Jonas Krautter (Karlsruhe Institute of Technology (KIT), Germany), and Mehdi B. Tahoori (Karlsruhe Institute of Technology (KIT), Germany)</i>	

Seamless Physical Implementation of ASIC Hierarchical Integrated Scan Architecture	339
<i>Bambang Suparjo (Intel Corp., USA), Jugantor Chetia (Intel Corp., USA), and Ankit R Shah (Intel Corp., USA)</i>	

Session 6A

Security EDA Extension through P1687.1 and 1687 Callbacks	344
<i>Michele Portolan (University of Grenoble Alpes, CNRS, France), Vincent Reynaud (University of Grenoble Alpes, CNRS, France), Paolo Maistri (University of Grenoble Alpes, CNRS, France), Regis Leveugle (University of Grenoble Alpes, CNRS, France), and Giorgio Di Natale (University of Grenoble Alpes, CNRS, France)</i>	
Accessing General IEEE Std. 1687 Networks via Functional Ports	354
<i>Erik Larsson (Lund University, Sweden), Prathamesh Murali (Lund University, Sweden), and Zilin Zhang (Lund University, Sweden)</i>	

Session 6B

Summing Node and False Summing Node Methods: Accurate Operational Amplifier AC Characteristics Testing without Audio Analyzer	364
<i>Daisuke Iimori (Gunma University, Japan), Takayuki Nakatani (Gunma University, Japan), Shogo Katayama (Gunma University, Japan), Gaku Ogihara (Gunma University, Japan), Akemi Hatta (Gunma University, Japan), Anna Kuwana (Gunma University, Japan), Keno Sato (ROHM Semiconductor, Japan), Takashi Ishida (ROHM Semiconductor, Japan), Tamotsu Ichikawa (ROHM Semiconductor, Japan), Jianglin Wei (Gunma University, Japan), Yujie Zhao (Gunma University, Japan), Tri Tran (v), Kazumi Hatayama (Gunma University, Japan), and Haruo Kobayashi (Gunma University, Japan)</i>	
Automatic Verification of Mixed-Signal ATE Test Programs Using Device Variation	374
<i>Franziska Mayer (Chemnitz University of Technology, Germany), Christian Schott (Chemnitz University of Technology, Germany), Enrico Billich (Chemnitz University of Technology, Germany), Saeid Yazdani (Chemnitz University of Technology, Germany), Ulrich Heinkel (Chemnitz University of Technology, Germany), Georg Daler (Infineon Technologies AG, Germany), Bernhard Ruf (Infineon Technologies AG, Germany), Ricardo Pannuzzo (Infineon Technologies AG, Germany), and Wolfgang Dickenscheid (Infineon Technologies Dresden GmbH & Co. KG, Germany)</i>	
Background Receiver IQ Imbalance Correction for In-Field and Post-Production Testing and Calibration	380
<i>Muslum Emir Avci (Arizona State University, USA) and Sule Ozev (Arizona State University, USA)</i>	

Session 6C

Hierarchical Failure Modeling and Machine Learning Assisted Correction of Electro-Mechanical Subsystem Failures in Autonomous Vehicles	389
<i>Chandramouli N Amarnath (Georgia Institute of Technology, USA), Md Imran Momtaz (Georgia Institute of Technology, USA), and Abhijit Chatterjee (Georgia Institute of Technology, USA)</i>	

Exploiting Application Tolerance for Functional Safety	399
<i>Prasanth V (Texas Instruments (India) Pvt. Ltd., India & Indian Institute of Science, India), Rubin Parekhji (Texas Instruments (India) Pvt. Ltd., India), and Bharadwaj Amrutur (Indian Institute of Science, India & Indian Institute of Science, India)</i>	
Compositional Fault Propagation Analysis in Embedded Systems Using Abstract Interpretation.....	409
<i>Christian Bartsch (TU Kaiserslautern, Germany), Stephan Wilhelm (AbsInt Angewandte Informatik GmbH, Germany), Daniel Kästner (AbsInt Angewandte Informatik GmbH, Germany), Dominik Stoffel (TU Kaiserslautern, Germany), and Wolfgang Kunz (TU Kaiserslautern, Germany)</i>	
Author Index	419